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| APPLICATION NO.            | FILING DATE                    | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO.           | CONFIRMATION NO. |
|----------------------------|--------------------------------|----------------------|-------------------------------|------------------|
| 09/892,225                 | 06/25/2001                     | Shunpei Yamazaki     | 07977/279001/US5023/5025 1969 |                  |
| 26171<br>FISH & RICHA      | 7590 01/10/2008<br>ARDSON P.C. | EXAMINER             |                               |                  |
| P.O. BOX 1022              |                                | SONG, MATTHEW J      |                               |                  |
| MINNEAPOLIS, MN 55440-1022 |                                |                      | ART UNIT                      | PAPER NUMBER     |
|                            |                                |                      | 1792                          |                  |
|                            |                                |                      |                               |                  |
|                            |                                |                      | MAIL DATE                     | DELIVERY MODE    |
|                            |                                |                      | 01/10/2008                    | PAPER            |

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

|  | Application No.   | Applicant(s)  |  |  |
|--|---|---|--|--|
|  | 09/892,225  | YAMAZAKI ET AL.   |  |  |
| Office Action Summary  | Examiner  | Art Unit  |  |  |
|  | Matthew J. Song   | 1792  |  |  |
| The MAILING DATE of this communication app Period for Reply  |   | correspondence address  |  |  |
| A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period w  - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).                             | ATE OF THIS COMMUNICATION  Se(a). In no event, however, may a reply be rill apply and will expire SIX (6) MONTHS from cause the application to become ABANDON | ON.<br>timely filed<br>om the mailing date of this communication.<br>NED (35 U.S.C. § 133). |  |  |
| Status   |   |   |  |  |
| Responsive to communication(s) filed on <u>30 Oc</u> This action is <b>FINAL</b> . 2b) ☑ This     Since this application is in condition for alloware closed in accordance with the practice under E   | action is non-final.<br>nce except for formal matters, p  |   |  |  |
| Disposition of Claims  |   |   |  |  |
| 4)  Claim(s) 15-19,29-31,35,36,39-46,49-54,57-68 4a) Of the above claim(s) is/are withdraw 5)  Claim(s) is/are allowed. 6)  Claim(s) 15-19,29-31,35,36,39-46,49-54,57-68 7)  Claim(s) is/are objected to. 8)  Claim(s) are subject to restriction and/or Application Papers  9)  The specification is objected to by the Examiner 10)  The drawing(s) filed on is/ are: a)  access   | vn from consideration.  71-76 and 95-100 is/are reject election requirement.  | ed.   |  |  |
| Applicant may not request that any objection to the one Replacement drawing sheet(s) including the correction of the oath or declaration is objected to by the Explanation is objected to by the Explanation is objected.  | drawing(s) be held in abeyance. So  | tee 37 CFR 1.85(a).<br>Objected to. See 37 CFR 1.121(d).                                    |  |  |
| Priority under 35 U.S.C. § 119   |   |   |  |  |
| 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).  a) All b) Some * c) None of:  1. Certified copies of the priority documents have been received.  2. Certified copies of the priority documents have been received in Application No.  3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).  * See the attached detailed Office action for a list of the certified copies not received. |   |   |  |  |
| Attachment(s)  1) Notice of References Cited (PTO-892)  2) Notice of Draftsperson's Patent Drawing Review (PTO-948)  3) Information Disclosure Statement(s) (PTO/SB/08)  Paper No(s)/Mail Date 10/30/07.   | 4) Interview Summa Paper No(s)/Mail 5) Notice of Informa 6) Other:  | Date  |  |  |

Application/Control Number:

09/892,225 Art Unit: 1792

### **DETAILED ACTION**

## Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 10/30/2007 has been entered.

## **Double Patenting**

2. The nonstatutory double patenting rejection is based on a judicially created doctrine grounded in public policy (a policy reflected in the statute) so as to prevent the unjustified or improper timewise extension of the "right to exclude" granted by a patent and to prevent possible harassment by multiple assignees. A nonstatutory obviousness-type double patenting rejection is appropriate where the conflicting claims are not identical, but at least one examined application claim is not patentably distinct from the reference claim(s) because the examined application claim is either anticipated by, or would have been obvious over, the reference claim(s). See, e.g., *In re Berg*, 140 F.3d 1428, 46 USPQ2d 1226 (Fed. Cir. 1998); *In re Goodman*, 11 F.3d 1046, 29 USPQ2d 2010 (Fed. Cir. 1993); *In re Longi*, 759 F.2d 887, 225 USPQ 645 (Fed. Cir. 1985); *In re Van Ornum*, 686 F.2d 937, 214 USPQ 761 (CCPA 1982); *In re Vogel*, 422 F.2d 438, 164 USPQ 619 (CCPA 1970); and *In re Thorington*, 418 F.2d 528, 163 USPQ 644 (CCPA 1969).

A timely filed terminal disclaimer in compliance with 37 CFR 1.321(c) or 1.321(d) may be used to overcome an actual or provisional rejection based on a nonstatutory double patenting ground provided the conflicting application or patent either is shown to be commonly owned with this application, or claims an invention made as a result of activities undertaken within the scope of a joint research agreement.

Effective January 1, 1994, a registered attorney or agent of record may sign a terminal disclaimer. A terminal disclaimer signed by the assignee must fully comply with 37 CFR 3.73(b).

3. Claims 15-19, 29-31, 35-36, 39-46, 49-54, 57-68, 71-76, and 95-100 are rejected on the ground of nonstatutory obviousness-type double patenting as being unpatentable over claims 1-

Art Unit: 1792

127 of U.S. Patent No. 6,913,956 ('956) in view of Burghartz et al (US 5,461,250). '956 claims a method of forming an amorphous semiconductor film; adding a catalytic element; conducing a first heat treatment; forming a semiconductor film containing a rare gas element; moving the catalytic element to the semiconductor film containing the rare gas element by a second heat treatment (claim 1). The second heat treatment is defined in the specification to be a heat treatment conducted in a nitrogen atmosphere (col 11, ln 30-55). '956 does not claim a first and second amorphous semiconductor film or a gate insulating film on the second crystalline semiconductor film.

In a method of forming a SiGe thin film transistor device, note entire reference, Burghartz et al teaches forming and patterning a bottom gate electrode; growing a bottom gate insulator; depositing a thin amorphous Si layer; depositing a SiGe channel layer thereon; depositing a Si layer on the SiGe layer; performing a recrystallization of the SiGe and Si layers; and growing a top gate insulator after recrystallization (Fig 1 and Fig 4). Burghartz et al also teaches the SiGe layer has a concentration of Ge of about 10-50%, which overlaps applicant's claimed range of 0.1-10%, and overlapping ranges are held to be prima facie obvious (MPEP 2144.05). Burghartz et al also teaches recrystallization of amorphous SiGe and Si layers (col 7, ln 55-67 and col 8, ln 60-65).

It would have been obvious to a person of ordinary skill in the art at the time of the invention to modify '956 using the semiconductor layer taught by Burhartz et al to form a useful SiGE TFT (col 5, ln 30-65).

Art Unit: 1792

4. Claims 15-19, 29-31, 35-36, 39-46, 49-54, 57-68, 71-76, and 95-100 are rejected on the ground of nonstatutory obviousness-type double patenting as being unpatentable over claims 1-70 of U.S. Patent No. 7,115,453 in view of Burghartz et al (US 5,461,250). '453 claims a method of forming an amorphous semiconductor film; adding a material to promote crystallization; conducing a first heat treatment; forming a semiconductor film containing a rare gas element; performing gettering through a second heating process thereby moving the metal to the second semiconductor film containing a rare gas element (claim 1). Gettering is defined in the specification to be a heat treatment conducted in a nitrogen atmosphere (col 10, ln 35-55). '453 does not claim a first and second amorphous semiconductor film or a gate insulating film on the second crystalline semiconductor film.

In a method of forming a SiGe thin film transistor device, note entire reference, Burghartz et al teaches forming and patterning a bottom gate electrode; growing a bottom gate insulator; depositing a thin amorphous Si layer; depositing a SiGe channel layer thereon; depositing a Si layer on the SiGe layer; performing a recrystallization of the SiGe and Si layers; and growing a top gate insulator after recrystallization (Fig 1 and Fig 4). Burghartz et al also teaches the SiGe layer has a concentration of Ge of about 10-50%, which overlaps applicant's claimed range of 0.1-10%, and overlapping ranges are held to be prima facie obvious (MPEP 2144.05). Burghartz et al also teaches recrystallization of amorphous SiGe and Si layers (col 7, ln 55-67 and col 8, ln 60-65).

It would have been obvious to a person of ordinary skill in the art at the time of the invention to modify '453 using the semiconductor layer taught by Burhartz et al to form a useful SiGE TFT (col 5, ln 30-65).

Art Unit: 1792

5. Claims 15-19, 29-31, 35-36, 39-46, 49-54, 57-68, 71-76, and 95-100 are rejected on the ground of nonstatutory obviousness-type double patenting as being unpatentable over claims 1-70 of U.S. Patent No. 7,052,943 in view of Burghartz et al (US 5,461,250). '943 claims a method of forming an amorphous semiconductor film with a metal element; crystallizing the first amorphous semiconductor layer; forming a second semiconductor film containing a rare gas element; and moving the metal to the second semiconductor film (claim 1). The moving of the metal to the second semiconductor film is accomplished, as defined in the specification, by a heat treatment conducted in a nitrogen atmosphere (col 11, ln 20-60 and col 12, ln 45-55). '943 does not claim a first and second amorphous semiconductor film or a gate insulating film on the second crystalline semiconductor film.

In a method of forming a SiGe thin film transistor device, note entire reference, Burghartz et al teaches forming and patterning a bottom gate electrode; growing a bottom gate insulator; depositing a thin amorphous Si layer; depositing a SiGe channel layer thereon; depositing a Si layer on the SiGe layer; performing a recrystallization of the SiGe and Si layers; and growing a top gate insulator after recrystallization (Fig 1 and Fig 4). Burghartz et al also teaches the SiGe layer has a concentration of Ge of about 10-50%, which overlaps applicant's claimed range of 0.1-10%, and overlapping ranges are held to be prima facie obvious (MPEP 2144.05). Burghartz et al also teaches recrystallization of amorphous SiGe and Si layers (col 7, ln 55-67 and col 8, ln 60-65).

Art Unit: 1792

It would have been obvious to a person of ordinary skill in the art at the time of the invention to modify '943 using the semiconductor layer taught by Burhartz et al to form a useful SiGE TFT (col 5, ln 30-65).

# Response to Arguments

- 6. Applicant's arguments, see the remarks, filed 10/30/2007, with respect to the prior art rejections over claims 15-19, 29-31, 35-36, 39-46, 49-54, 57-68, 71-76, and 95-100 have been fully considered and are persuasive. The rejection of claims 15-19, 29-31, 35-36, 39-46, 49-54, 57-68, 71-76, and 95-100 has been withdrawn. The prior art does not teach the newly added limitations.
- 7. Applicant's arguments with respect to claims 15-19, 29-31, 35-36, 39-46, 49-54, 57-68, 71-76, and 95-100 have been considered but are moot in view of the new ground(s) of rejection.

#### Conclusion

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Matthew J. Song whose telephone number is 571-272-1468. The examiner can normally be reached on M-F 9:00-5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Barr can be reached on 571-272-1414. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Art Unit: 1792

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Matthew J Song Examiner Art Unit 1792

MJS January 7, 2008

MICHAEL BARR

SUPERVISORY PATENT EXAMINER